

<b>Notice of References Cited</b>	Application/Control No. 10/572,839	Applicant(s)/Patent Under Reexamination TANAKA, HIDEO	
	Examiner RICHARD H. KIM	Art Unit 2871	Page 1 of 1

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*	B	US-7,176,994 b2	02-2007	Maeda et al.	349/113
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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